UNIVERSITAT POLITÈCNICA DE CATALUNYA

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Thorough characterization and analysis of a multispectral imaging system developed for colour measurement

Thesis

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Figure A7.1 (1) *MUNSELL R*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (2) *MUNSELL YR*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (3) *MUNSELL* **Y**: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (4) *MUNSELL GY*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (5) *MUNSELL G*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (6) *MUNSELL BG*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (7) *MUNSELL B*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (8) *MUNSELL PB*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (9) *MUNSELL P*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.1 (10) *MUNSELL RP*: Amplitude of the DFT's components of the colour patches with the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.2 (1) *MUNSELL R*: Accumulated contribution of the DFT's harmonics for the colour patches having the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Figure A7.2 (2) *MUNSELL YR*: Accumulated contribution of the DFT's harmonics for the colour patches having the five worst and the best (a) ΔE^*_{ab} and (b) RMSE values.



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Central Wavelength (nm)	FWHM (nm)	Peak Transmittance (%)	Supplier
400	10	40	OptoSigma
400	40	40	OptoSigma
400	50	55	Edmund Optics Optics
400	40	35	CVI Laser Laser
400	70	55	CVI Laser Laser
405	10	40	Edmund Optics
410	10	40	Edmund Optics
410	10	35	CVI Laser Laser
415	10	40	Edmund Optics
415	10	35	CVI Laser
420	10	40	Edmund Optics / CVI Laser
430	10	40	Edmund Optics / CVI Laser
430	10	35	CVI Laser
436	10	40	Edmund Optics
440	10	40	CVI Laser
442	10	40	Edmund Optics
450	10	45	Edmund Optics / OptoSigma / CVI Laser
450	40	50	OptoSigma
450	80	60	Edmund Optics
450	10	40	CVI Laser
450	25	45	CVI Laser
450	40	45	CVI Laser
450	70	55	CVI Laser
455	10	45	Edmund Optics
458	10	45	Edmund Optics
460	10	45	CVI Laser
467	10	45	Edmund Optics
470	10	45	Edmund Optics / CVI Laser
477	10	45	Edmund Optics
480	10	45	Edmund Optics / CVI Laser
486	10	45	Edmund Optics
488	10	45	CVI Laser
490	10	45	Edmund Optics
492	10	45	CVI Laser
493	10	45	OptoSigma
500	10	50	Edmund Optics
500	40	50	Edmund Optics / CVI Laser
500	80	60	CVI Laser
500	10	45	CVI Laser
500	10	40	CVI Laser
500	25	50	CVI Laser
500	70	60	CVI Laser
505	10	45	Edmund Optics
508	10	45	CVI Laser
510	10	45	Edmund Optics

Appendix 8 Database of selected commercially available interference filters (Edmund Optics, OptoSigma, CVI Laser Laser)

Central Wavelength (nm)	FWHM (nm)	Peak Transmittance (%)	Supplier
515	10	45	CVI Laser
520	10	45	CVI Laser
520	10	40	CVI Laser
527	10	45	Edmund Optics
530	10	45	CVI Laser
532	10	45	Edmund Optics
535	10	45	CVI Laser
540	10	45	Edmund Optics / OptoSigma
546	10	45	OptoSigma
550	10	50	Edmund Optics / CVI Laser
550	40	50	CVI Laser
550	80	60	CVI Laser
550	10	45	CVI Laser
550	25	50	CVI Laser
550	70	60	Edmund Optics
560	10	50	CVI Laser
568	10	45	CVI Laser
570	10	50	Edmund Optics
577	10	50	CVI Laser
580	10	45	CVI Laser
580	10	50	Edmund Optics
585	10	50	CVI Laser
589	10	45	OptoSigma
590	10	50	OptoSigma
600	10	50	Edmund Optics / CVI Laser
600	40	50	Edmund Optics / CVI Laser
600	80	60	CVI Laser
600	10	45	CVI Laser
600	25	50	CVI Laser
600	70	60	CVI Laser
610	10	45	Edmund Optics
610	10	50	CVI Laser
620	10	45	Edmund Optics / CVI Laser
620	10	50	CVI Laser
630	10	50	Edmund Optics
632	10	45	CVI Laser
636	10	45	Edmund Optics
640	10	50	Edmund Optics
640	10	45	Edmund Optics / OptoSigma
647	10	45	OptoSigma
650	10	50	Edmund Optics / CVI Laser
650	40	50	Edmund Optics / CVI Laser
650	80	60	CVI Laser
650	10	45	CVI Laser
650	25	50	CVI Laser

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Central Wavelength (nm)	FWHM (nm)	Peak Transmittance (%)	Supplier
650	70	60	CVI Laser
656	10	50	CVI Laser
660	10	50	CVI Laser
670	10	50	CVI Laser
670	25	50	CVI Laser
670	40	50	Edmund Optics
670	70	60	CVI Laser
671	10	50	Edmund Optics / CVI Laser
675	20	50	CVI Laser
676	10	50	CVI Laser
680	10	50	Edmund Optics
685	10	50	CVI Laser
690	10	50	Edmund Optics / OptoSigma
694	10	50	OptoSigma
700	10	50	Edmund Optics / CVI Laser
700	40	50	Edmund Optics / CVI Laser
700	80	60	Edmund Optics / CVI Laser
700	25	50	CVI Laser
700	70	60	CVI Laser
400	10	40	OptoSigma
400	40	40	OptoSigma

Appendix 8 Database of selected commercially available interference filters (Edmund Optics, OptoSigma, CVI Laser Laser)

Internet Sources:

Edmund Optics:

http://www.edmundoptics.com/onlinecatalog/displayproduct.cfm?productID=1936 http://www.edmundoptics.com/onlinecatalog/displayproduct.cfm?productID=1903

OptoSigma:

http://www.optosigma.com/miva/merchant.mv?Screen=PROD&Store_Code=OS&Product_Code=pg19 5-197

CVI Laser:

http://www.cvilaser.com/Catalog/Pages/Template2.aspx?pcid=206&filter=0

Figure A9 (1) Reflectance spectra of the 28 pairs of textile samples provided by the INTEXTER.



Figure A9 (2) Reflectance spectra of the 28 pairs of textile samples provided by the INTEXTER.



Appendix 9 Reflectance spectra of the 28 pairs of textile samples provided by the INTEXTER



Figure A9 (3) Reflectance spectra of the 28 pairs of textile samples provided by the INTEXTER.